

# PB1200

## specifications



<b>utilities</b>	<p><b>AC Input Power:</b> 115 VAC 50/60 Hz, Single Phase @ 15A service or 230 VAC 50/60 Hz, Single Phase @ 15A</p> <p><b>AC Fuse:</b> 10A @ 115 VAC; 5A @ 240 VAC</p> <p><b>Vacuum Supply:</b> Input: <math>\geq 25"</math> of Mercury</p> <p><b>Requirements:</b> Consumption: 3 SCFM</p>																		
<b>mechanical specifications</b>	<p><b>Physical Dimensions:</b> Height: 62" (157.5 cm) (includes bench &amp; monitor)          Width: 45" (114 cm)          Depth: 43" (109 cm)          Weight: 450 lbs. (205 kg)          Tie Down: Earthquake Tie Down Provided          Portability: Bench-top Configuration</p> <p><b>Measurement Area / Stage:</b> Flatness: <math>\leq 0.0005"</math> TIR          Raised Planarity Test Pin: 3 mil Std. (1-5 mil optional) Customer Changeable          Maximum Probe Array: 3" x 3"          Gram Force Measurement: Optional          Gram Force Pin: 3 mil Std. (1-5 mil optional) Customer Changeable          Stage: X, Y Ball Screw Drive          Max Total Probe Tip Force: 100 lb (45.4 kg)          Travel: X = 6" (15.2 cm), Y = 6" (15.2 cm), Z = 2.0" (5.08 cm)</p> <p><b>Probe Card Interface:</b> Accommodates: Various ITC Probe Card Adaptor Plates          Mounting: Vacuum Attachment</p> <p><b>Video System:</b> Alignment Resolution: 0.5 micron          Type: B/W          No. of Probes / Capture: 1 - Single Pin, 4-25 - Multi-Pin Capture (Pitch Dependent)          Min. Probe Size: 0.2 mil          Max. Probe Size: 10 mil          Binocular Microscope: Leica MZ80 or equivalent, standard (other types optional)</p>																		
<b>pc computer</b>	<p><b>Standard Hardware:</b> Processor: Pentium 4, <math>\geq 2.0</math> GHz Industrial Computer          Operating System: Windows XP Pro w/ODBC Database for Programs &amp; Data          Hard Drive: <math>\geq 60</math> Gb          Memory: <math>\geq 512</math> MB PC 100          Peripherals: 3.5" Floppy, CD-RW ROM          Monitor: High Resolution 15" Color LCD, CE Approved          I/O: Ethernet Card, USB (2 Hubs)</p>																		
<b>environmental requirements</b>	<p><b>Ambient Temperature:</b> Operating: 68°F +10°F/-5°F (20°C + 6°C/-3°C)          Highest Accuracy &amp; Repeatability: 68°F <math>\pm 2</math>°F (20°C <math>\pm 1</math>°C)          Storage: 20°F - 102°F (-6°C - 39°C)</p> <p><b>Cleanliness:</b> Recommended: Class 10,000 (or better) Clean Room</p> <p><b>Humidity:</b> Operating: 0% - 70% RH          Storage: 0% - 80% RH          (Non-condensing)</p>																		
<b>probe card adaptors</b>	<p><b>Weight:</b> Adapter: Approx. 15 lb. (6.8 kg)          Retainer: Approx. 10 lb. (4.5 kg)          Max. Probe Card Diameter: 17" (43.2 cm)          Edge Cards: 4" to 8" (10 to 20 cm)          Tools Req'd to Change Card: None for most probe card styles          Calibration: Adjustable Planarity to 0.1 mil (2.54 microns)</p>																		
<b>general</b>	<p><b>Compliance Standards:</b> Semi S2-93 &amp; S2-93A          Safety Guidelines: Standard          Semi S8-95 Ergo Guidelines: Standard          CE Mark: Standard          Other Standards: ANSI/RIA R15.06-1992 (Robotic Safety), NIST Q, ASTM 5, FCC 47, EMC Directive 89/336/EEC, EN 50082-1:1992 (ESD), EN 55022:1988 (Emissions), EN 60555-2:1992 (Harmonics), EN 61000-3-3:1996 (Flicker)          NIST Traceability: Standard</p>																		
<b>accuracy specification</b>	<table border="1"> <thead> <tr> <th>Test</th> <th>Travel</th> <th>Load</th> <th>Resolution</th> <th>Accuracy (<math>\pm</math>)</th> <th>Repeatability (<math>\pm</math>) <math>3\sigma</math></th> </tr> </thead> <tbody> <tr> <td><b>Planarity</b></td> <td>2.0" (Z)</td> <td>50 lbs.</td> <td>0.1 micron</td> <td>3.0 micron (0.12 mils)</td> <td>2.0 micron (0.08 mil)</td> </tr> <tr> <td><b>Alignment</b></td> <td>6" x 6" (X x Y)</td> <td>50 lbs.</td> <td>0.1 micron</td> <td>2.0 micron (0.08 mils)</td> <td>1.2 micron (0.05 mil)</td> </tr> </tbody> </table>	Test	Travel	Load	Resolution	Accuracy ( $\pm$ )	Repeatability ( $\pm$ ) $3\sigma$	<b>Planarity</b>	2.0" (Z)	50 lbs.	0.1 micron	3.0 micron (0.12 mils)	2.0 micron (0.08 mil)	<b>Alignment</b>	6" x 6" (X x Y)	50 lbs.	0.1 micron	2.0 micron (0.08 mils)	1.2 micron (0.05 mil)
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Note: Specifications are subject to change without notice.

F.S. = Full Scale of the Given Range

### FSA-TECHNOLOGY INC.

Unit 2ARLI Bldg., South Point, Banay-banay Cabuyao  
 City Laguna, Philippines 4025  
 Tel #: +63 49 5446972 Email: fsasales@fsa-tech.com

PRODUCTIVITY SOLUTIONS FOR PROBE & TEST

spec sheet